

N-Channel Super Junction Power MOSFET $\,\,{\rm IV}$

General Description

The series of devices use advanced trench gate super junction technology and design to provide excellent R_{DS(ON)} with low gate charge. This super junction MOSFET fits the industry's AC-DC SMPS requirements for PFC, AC/DC power conversion, and industrial power applications.

Features

- Optimized body diode reverse recovery performance
- •Low on-resistance and low conduction losses
- Small package
- ●Ultra Low Gate Charge cause lower driving requirements
- ●100% Avalanche Tested
- ●ROHS compliant

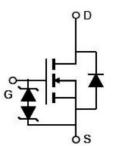
Application

- Power factor correction (PFC)
- Switched mode power supplies(SMPS)
- Uninterruptible Power Supply (UPS)
- LLC Half-bridge

Package Marking And Ordering Information

Device	Device Package	Marking	
NCE65N330	TO-220-3L	NCE65N330	

V _{DS min@Tjmax}	710	V
RDS(ON)TYP	300	mΩ
ID	11	A
Qg	17	nC



Schematic diagram



Table 1. Absolute Maximum Ratings (T_c=25℃)

Parameter	Symbol	Value	Unit
Drain-Source Voltage (VGS=0V)	VDS	650	V
Gate-Source Voltage (VDS=0V) AC (f>1 Hz)	Vgs	±30	V
Gate-Source Voltage (VDS=0V) DC	Vgs	±20	V
Continuous Drain Current at Tc=25°C	I _{D (DC)}	11	A
Continuous Drain Current at Tc=100°C	I _{D (DC)}	7.7	A
Pulsed drain current ^(Note 1)	I _{DM (pluse)}	44	A
Maximum Power Dissipation(Tc=25°C)	PD	107	W
Derate above 25°C		0.71	W/°C
Avalanche current ^(Note 2)	I _{AS}	3	A
Drain Source voltage slope, V _{DS} ≤480 V,	dv/dt	50	V/ns
Reverse diode dv/dt, V _{DS} ≤480 V,I _{SD} <i<sub>D</i<sub>	dv/dt	15	V/ns
Operating Junction and Storage Temperature Range	TJ,TSTG	-55+175	°C

* limited by maximum junction temperature



Table 2. Thermal Characteristic

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case (Maximum)	R _{thJC}	1.4	°C /W
Thermal Resistance, Junction-to-Ambient (Maximum)	R _{thJA}	62	°C /W

Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	eter Symbol Condition		Min	Тур	Max	Unit
On/off states				•		
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =250µA	650			V
Zero Gate Voltage Drain Current(Tc=25°C)	I _{DSS}	V _{DS} =650V,V _{GS} =0V)V,V _{GS} =0V		1	μA
Zero Gate Voltage Drain Current(Tc=125℃)	I _{DSS}	V _{DS} =650V,V _{GS} =0V			100	μA
Gate-Body Leakage Current	I _{GSS}	V_{GS} =±20V, V_{DS} =0V			±200	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} ,I _D =250µA	3	3.5	4	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =5.5A		300	330	mΩ
Dynamic Characteristics						
Input Capacitance	Clss			847		pF
Output Capacitance	Coss	V _{DS} =50V,V _{GS} =0V, F=1.0MHz		31		pF
Reverse Transfer Capacitance	C _{rss}			4		pF
Total Gate Charge	Qg			17		nC
Gate-Source Charge	Qgs	V _{DS} =480V,I _D =5.5A,		4.4		nC
Gate-Drain Charge	Q _{gd}	V _{GS} =10V		4.9		nC
Gate plateau voltage	Vgp			5.4		V
Intrinsic gate resistance	Rg	f = 1 MHz open drain 1		18		Ω
Switching times	L.					
Turn-on Delay Time	t _{d(on)}			10		nS
Turn-on Rise Time	tr	V _{DD} =480V,I _D =5.5A,		7		nS
Turn-Off Delay Time	t _{d(off)}	R _G =1.7Ω,V _{GS} =10V		55		nS
Turn-Off Fall Time	t _f			8		nS
Source- Drain Diode Characteristics						
Source-drain current(Body Diode)	I _{SD}	T -25%0			11	Α
Pulsed Source-drain current(Body Diode)	I _{SDM}	Tc=25°C			44	Α
Forward On Voltage	V _{SD}	Tj=25°C,I _{SD} =11A,V _{GS} =0V 0.9		0.9	1.2	V
Reverse Recovery Time	t _{rr}			200		nS
Reverse Recovery Charge	Qrr	Tj=25°C,I _F =5.5A,		1.6		uC
Peak Reverse Recovery Current	Irrm	di/dt=100A/µs		16		Α

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature

2. Tj=25°C,VDD=50V,VG=10V, R_G=25 Ω



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (curves)

Figure1. Safe operating area

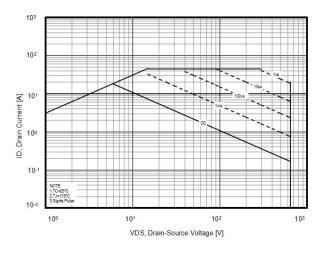


Figure3. Transfer characteristics

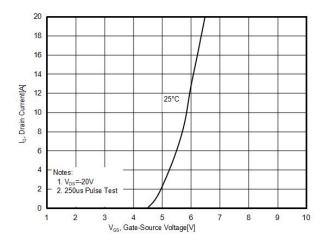


Figure 5. RDS(ON) vs Junction Temperature

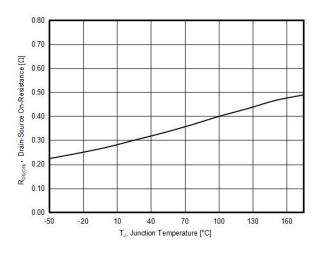


Figure2. Capacitance

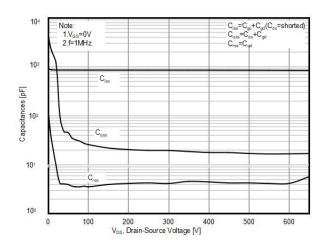


Figure4. Output characteristics

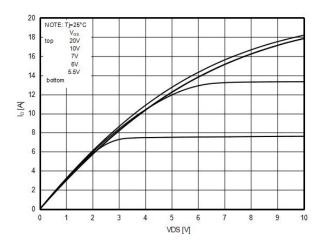


Figure6. BV_{DSS} vs Junction Temperature

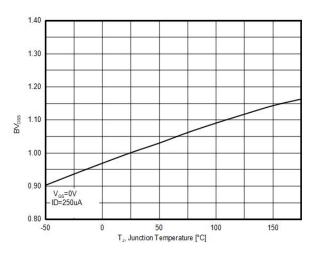




Figure7. Maximum I_D vs Junction Temperature

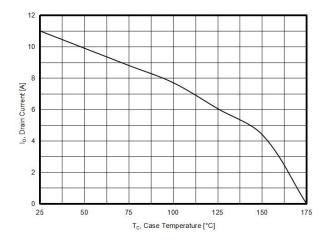


Figure8. Gate charge waveforms

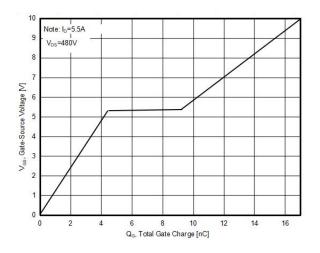


Figure9. Static drain-source on resistance

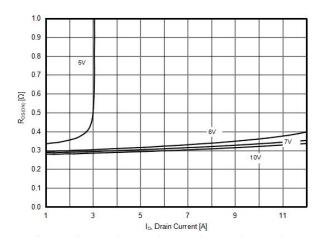
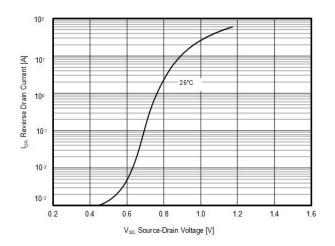


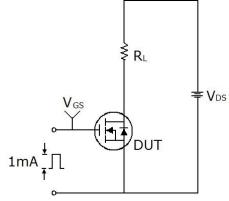
Figure10. Source-Drain Diode Forward Voltag

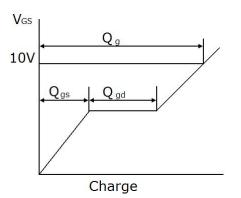




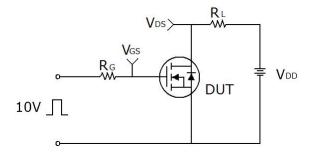
Test circuit

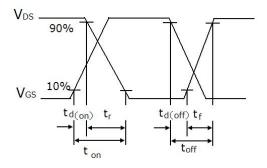
1) Gate charge test circuit & Waveform



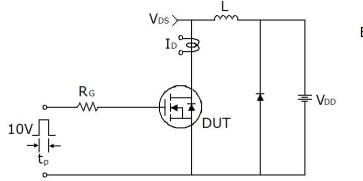


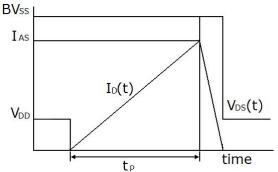
2) Switch Time Test Circuit:





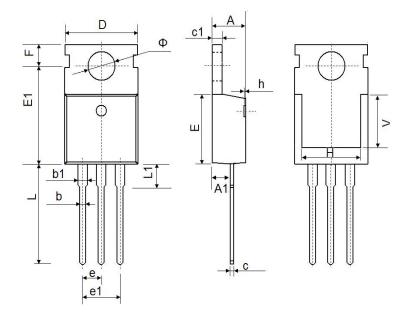
3) Unclamped Inductive Switching Test Circuit & Waveforms







TO-220-E Package Information



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max.	
A	4.20	4.60	0.165	0.181	
A1	2.25	2.55	0.089	0.100	
b	0.70	0.90	0.028	0.035	
b1	1.17	1.37	0.046	0.054	
С	0.33	0.65	0.013	0.026	
c1	1.20	1.40	0.047	0.055	
D	9.91	10.25	0.390	0.404	
E	8.95	9.75	0.352	0.384	
E1	12.80	12.90	0.504	0.508	
e	2.54	2.54BSC		BSC	
e1	5.08	5.08BSC		BSC	
F	2.65	2.95	0.104	0.116	
Н	7.90	8.10	0.311	0.319	
L	12.90	13.40	0.508	0.528	
L1	2.85	3.25	0.112	0.128	
Φ	3.40	3.80	0.134	0.150	



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